

<b>Notice of References Cited</b>	Application/Control No. 10/594,677		Applicant(s)/Patent Under Reexamination INOUE, TAKAO	
	Examiner Thuy V. Tran		Art Unit 2821	Page 1 of 1

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*	B	US-6,963,175 B2	11-2005	Archenhold et al.	315/291
*	C	US-4,076,977	02-1978	Tsunekawa et al.	250/206
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	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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